

Sheet 1 of 2

Form PTO-1449 (REV. 8-83)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 123857.00002		SERIAL NO. 10/695,304									
INFORMATION DISCLOSURE CITATION															
(Use several sheets if necessary)															
															
<table border="1"> <tr> <td colspan="2">APPLICANT Ana Martinez, et al.</td> <td colspan="2">EXAMINER Not Assigned GREGORY</td> </tr> <tr> <td colspan="2">FILING DATE October 28, 2003</td> <td colspan="2">GROUP A.U. 3661-3662</td> </tr> </table>								APPLICANT Ana Martinez, et al.		EXAMINER Not Assigned GREGORY		FILING DATE October 28, 2003		GROUP A.U. 3661-3662	
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U. S. PATENT DOCUMENTS															
Examiner INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	FILING DATE IF APPROPRIATE								
DG	A1	5,463,397	10/31/95	Frankot	342	25									
DG	A2	5,677,693	10/14/97	Frankot et al.	342	25									
FOREIGN PATENT DOCUMENTS															
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION								
							YES	NO							
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)															
DG	B1	Qian Lin et al., "Topography Estimation with Interferometric Synthetic Aperture Radar Using Fringe Detection", 1991 IEEE, 4 pgs.													
DG	B2	W.W. Bonitat, Jr. et al., "Interferometric Height Estimation of the Seafloor Via Synthetic Aperture Sonar in the Presence of Motion Errors", IEEE Proc.-Radar, Sonar Navig., vol. 147, No. 6, December 2000, pgs. 322-330.													
DG	B3	P. Piau, "Performances of the 3D-SAR Imagery", 1994 IEEE, 5 pgs.													
DG	B4	Johan Jacob Mohr et al., "Parametric Estimation of Time Varying Baselines in Airborne Interferometric SAR", 1996 IEEE, 3 pgs.													
DG	B5	David A. Yocky et al., "Repeat-Pass Dual-Antenna Synthetic Aperture Radar Interferometric Change Detection Post-Processing", 1997, Sandia National Laboratories SAND97-1198J, 13 pgs.													

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<p>* EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>			



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<i>DG</i>	B6	Robert Treuhart et al., "Estimating Vegetation and Surface Topographic Parameters from Multibaseline Radar Interferometry", 1996 IEEE, 3 pgs.					
<i>DG</i>	B7	Søren N. Madsen et al., "Topographic Mapping Using Radar Interferometry: Processing Techniques", IEEE Transactions on Geoscience and Remote Sensing, Vol. 31, No. 1, January 1993, pgs. 246-256.					
<i>DG</i>	B8	Dennis C. Ghiglia et al., "Interferometric Synthetic Aperture Radar Terrain Elevation Mapping from Multiple Observations", 1994, Sandia National Laboratories SAND94-0624C, 4 pgs.					
<i>DG</i>	B9	Vincent Mrstik, "Terrain Height Measurement Accuracy of Interferometric Synthetic Aperture Radars, IEEE Transactions on Geoscience and Remote Sensing, Vol. 34, No. 1, January 1996, pgs. 219-228.					
<i>DG</i>	B10	Richard E. Carande, "Estimating Ocean Coherence Time Using Dual-Baseline Interferometric Synthetic Aperture Radar", IEEE Transactions on Geoscience and Remote Sensing, Vol. 32, No. 4, July 1994, pgs. 846-854.					

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